

Docket No.

247943US-2X



IN RE APPLICATION OF:

Tatsuya KUNIKIYO, et al.

SERIAL NO:

10/760,449

GAU:

FILED:

January 21, 2004

EXAMINER:

FOR:

CAPACITANCE MEASUREMENT CIRCUIT

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

COMMISSIONER FOR PATENTS ALEXANDRIA, VIRGINIA 22313

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Applicant(s) wish to disclose the following information.

REFERENCES

The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.

☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

- Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.
- A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

- ☐ Each item of information contained in this information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- □ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number <u>15-0030</u>. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

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(Modified) PATENT AND TRADEMARK OFFICE			247943US-2X			10/760,449			
				APPLICANT					
LIST OF	REFE	RENCES CITED BY AP	PLICANT	Tatsuya KUNIKIY	O, et al.				
				FILING DATE			GROUP		
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				U.S. PATENT DOCUM	ENTS				
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME		CLASS	SUB FILING DATE CLASS IF APPROPRIATE		
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	AB	5,999,010	12/07/99	ARORA ET AL.					
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	AW	Jai-Hoon SIM, et al., 1998 Symposium on VLSI Technology Digest of Technical Papers, Pages 32-33, "THE IMPACT OF ISOLATION PITCH SCALING ON V _{th} FLUCTUATION IN DRAM CELL TRANSISTORS DUE TO NEIGHBORING DRAIN/SOURCE ELECTRIC FIELD PENETRATION," June 9-11, 1998							
	АХ	James C. CHEN, et al., Technical Digest of IEDM, pages 69-72, "AN ON-CHIP, ATTOFARAD INTERCONNECT CHARGE-BASED CAPACITANCE MEASUREMENT (CBCM) TECHNIQUE," 1996							
	AY	K. YAMADA, et al., 2003 Symposium on VLSI Technology Digest of Technical Papers, pages 111-112, "ACCURATE MODELING METHOD FOR DEEP SUB-MICRON Cu INTERCONNECT," June 10-12, 2003/Kyoto							
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LIST OF RELATED CASES

Docket Number	Serial or Patent Number	Filing or <u>Issue Date</u>	Inventor/ <u>Applicant</u>
PER CLIENT	10/355,068	01/31/03	YAMASHITA et al.
227009US2X	10/232,689	09/03/02	KUNIKIYO et al.
229544US2	10/287,537	11/05/02	OKAGAKI et al.
247943US2X*	10/760,449	01/21/04	KUNIKIYO et al.